



## Capability Analysis



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## References

- QS 9000
- QS 9000 (Measurement System Analysis (AIAG))
- IATF 16949

### ***9.1.1.1 Monitoring and measurement of manufacturing processes***

The organization shall perform process studies on all new manufacturing (including assembly or sequencing) processes to verify process capability and to provide additional input for process control, including those for special characteristics.

- VDA Booklet 4 and 5
- "Measurement System Capability" Reference Manual

# References

- Guidline ("Measurement System Capability" Reference Manual)

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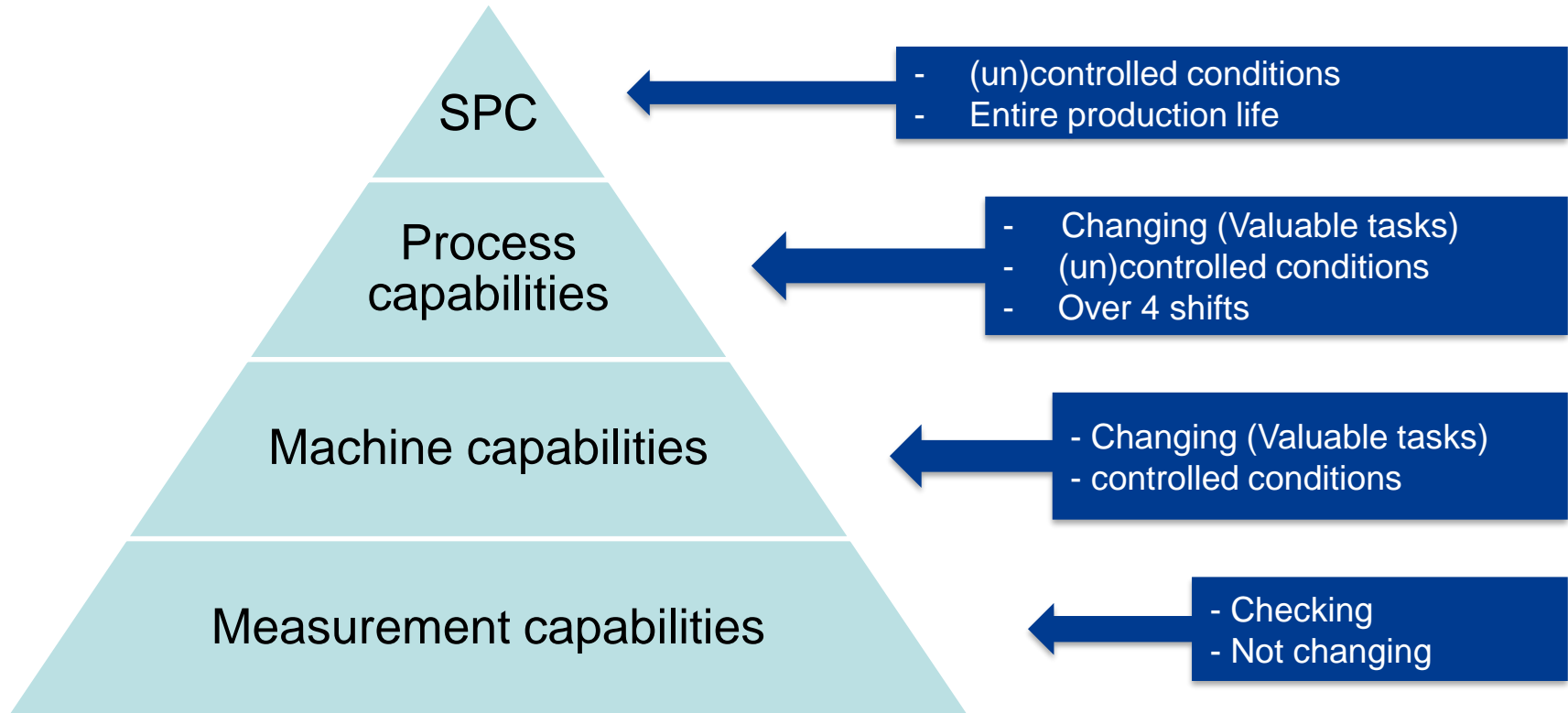
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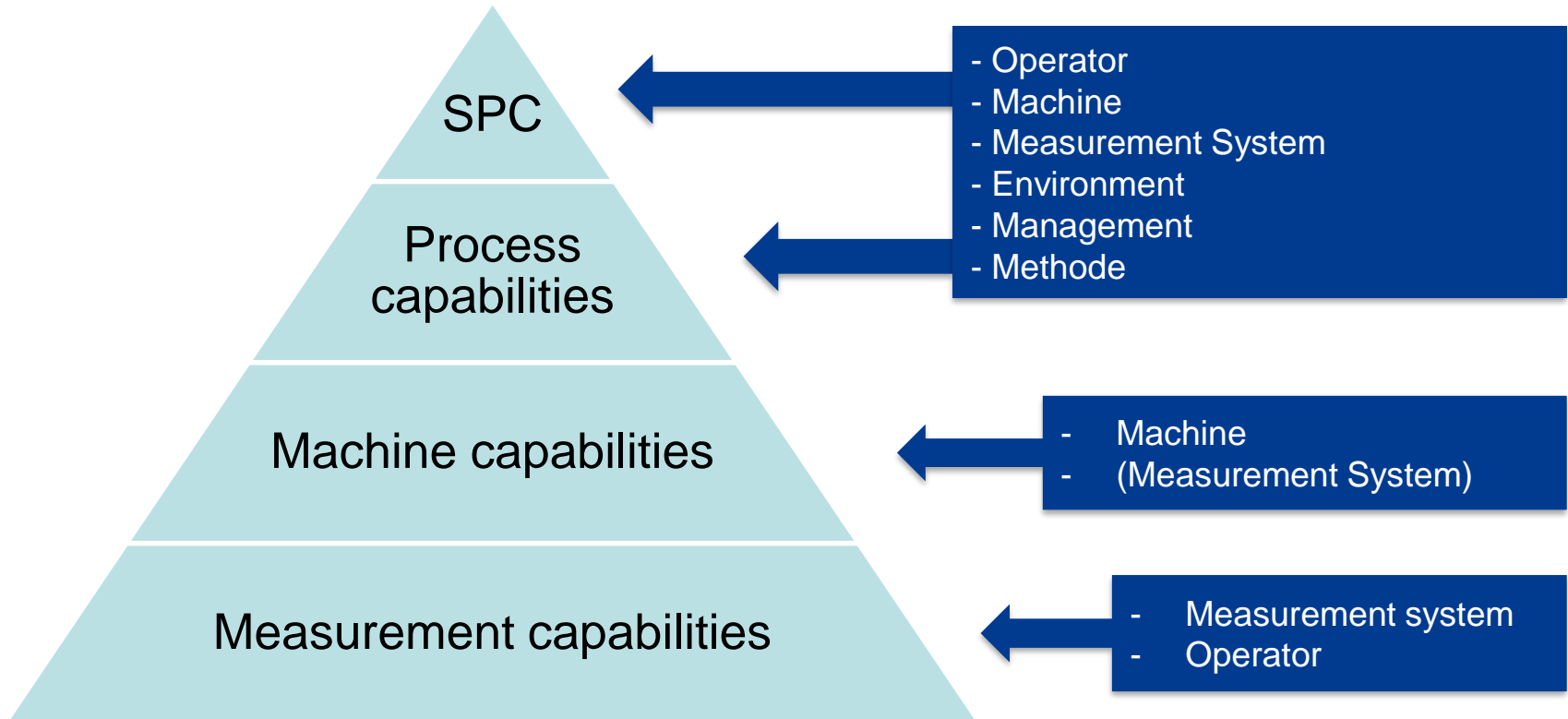
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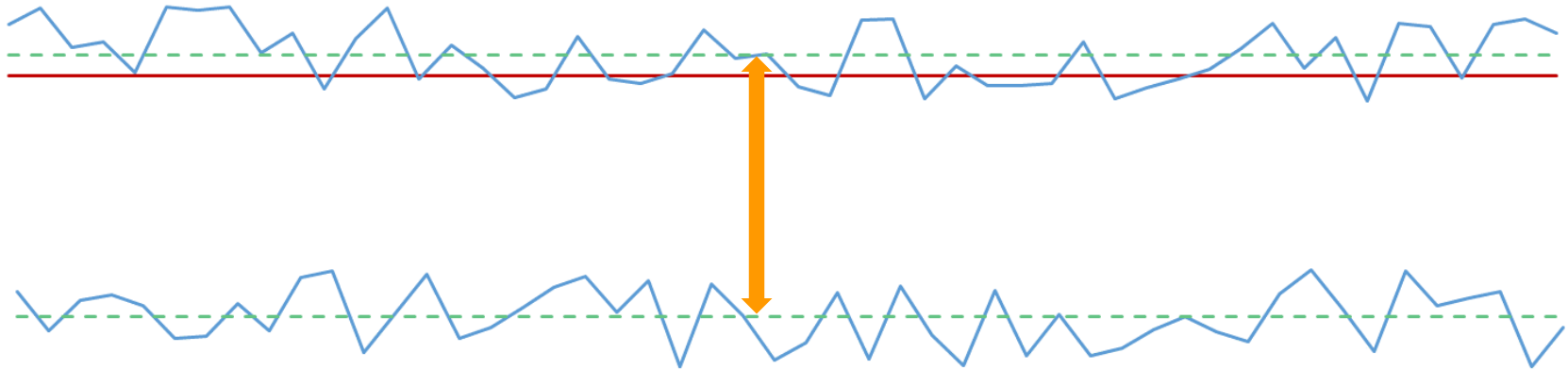
# Qualification Pyramid



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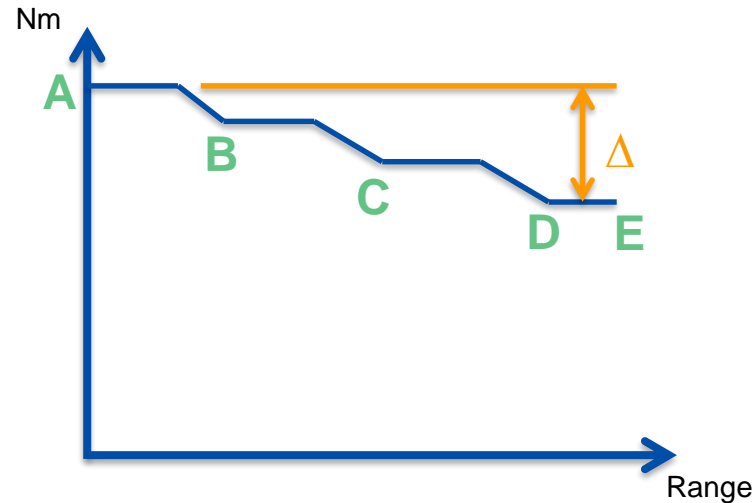
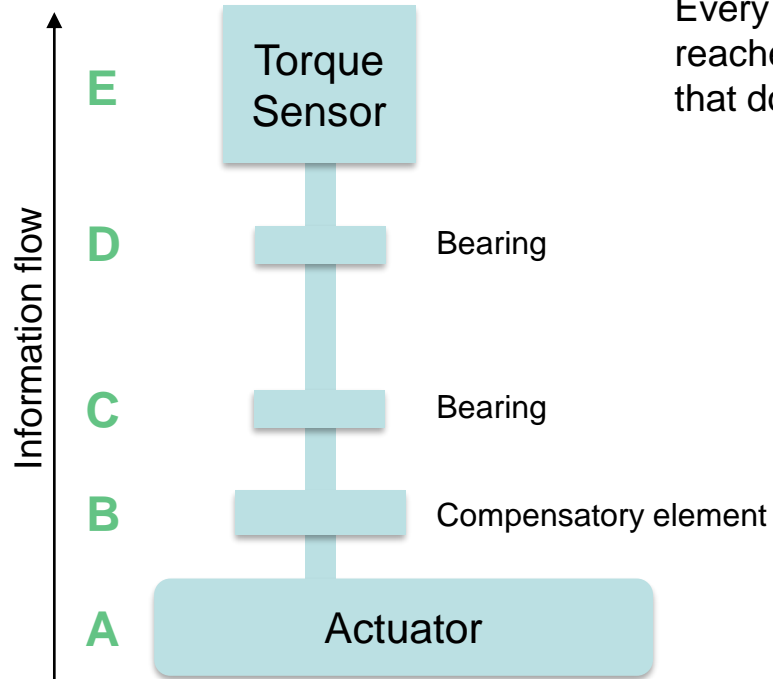
# Correlation and System influences



Different Measurement systems can capture different results. The need is to understand the reason for this difference.

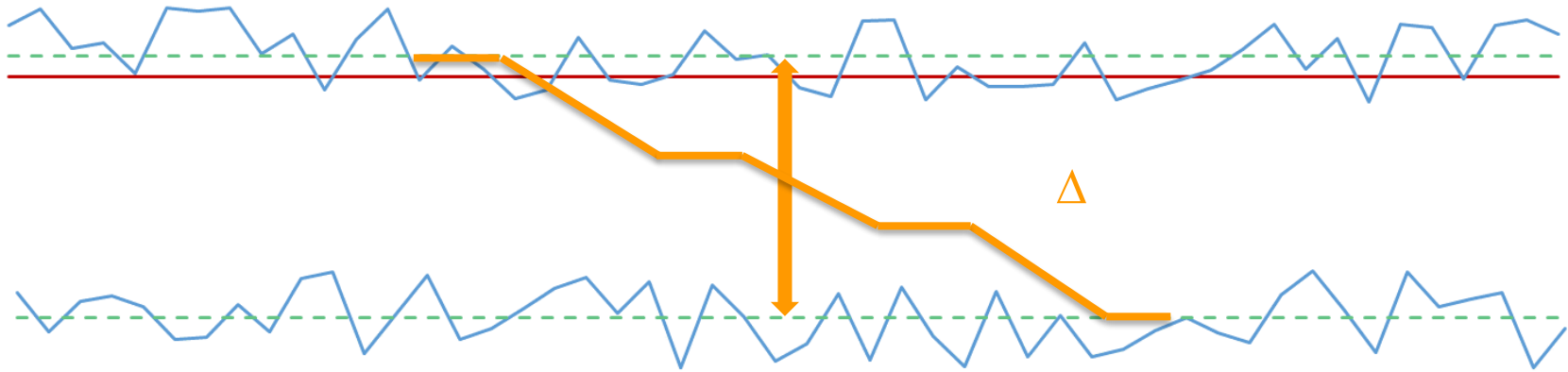
# Correlation and System influences

Every measuring system can only capture information that reaches a sensor. Unfortunately, there is always information that does not reach the sensor, e.g. due to friction.






# Correlation and System influences



This lack of information caused by systematic influences can lead to different coverage.

# Qualification Pyramid



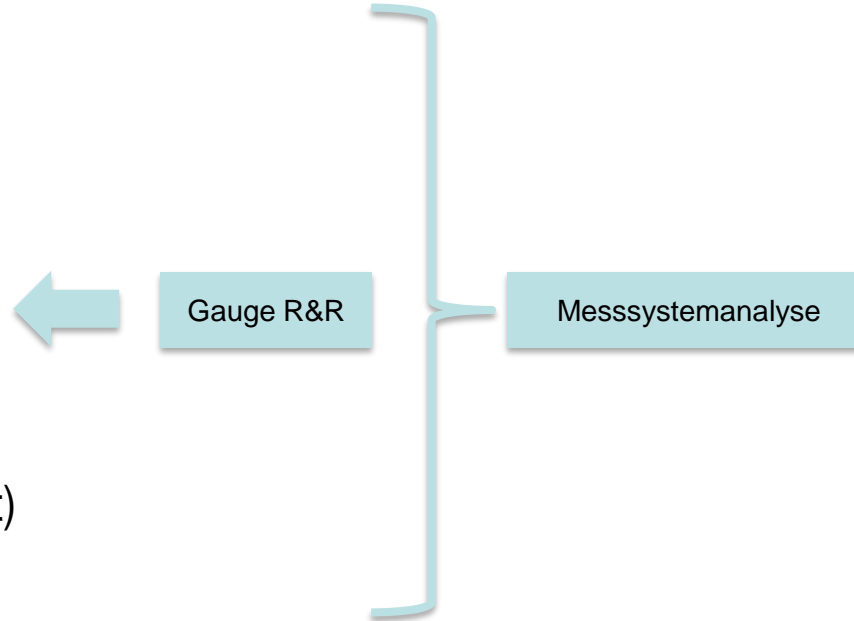
Measurement  
capabilities

## Measurement capability

- Method 1 (every equipment)
  - $C_g$
  - $C_{gk}$

- Method 2 (manual equipment)
  - R&R

- Method 3 (automatic equipment)
  - R&R



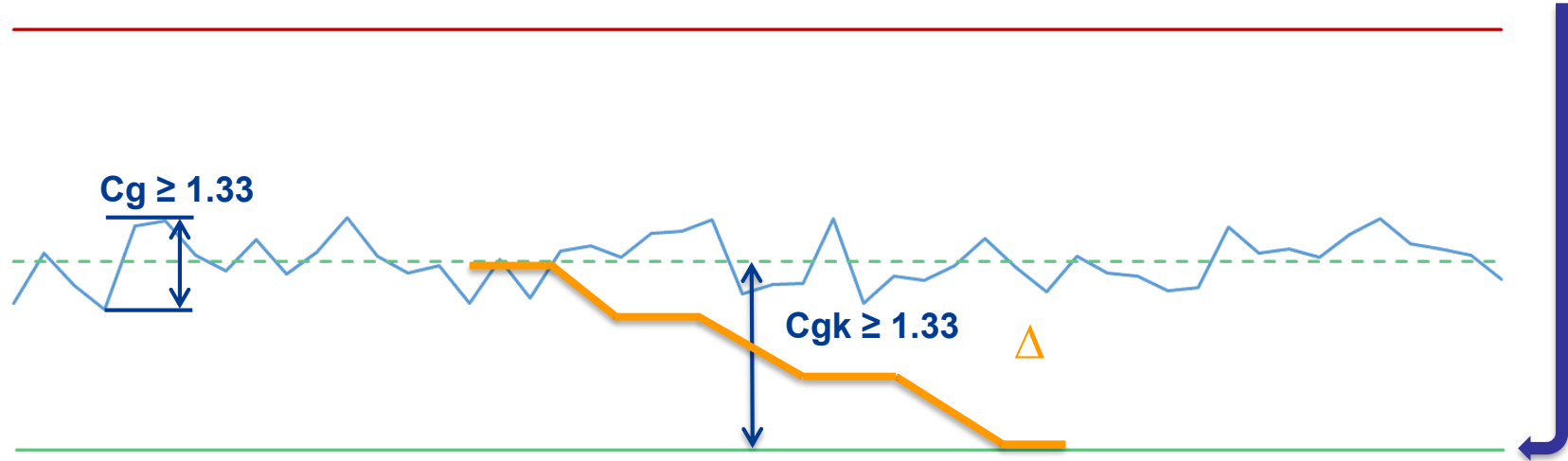
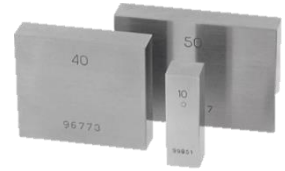
## Measurement capability Method 1

- Check 1 Part (Normal) 50 times
- Normal checked according DIN EN ISO/IEC 17025 (IATF requirement)



- Indices:  $C_g$ ;  $C_{gk}$  (Capability gauge; Capability gauge Katayori)
- Detected Influences: Measurement system

# Measurement capability Method 1



Cg: Indicator for the spread width.

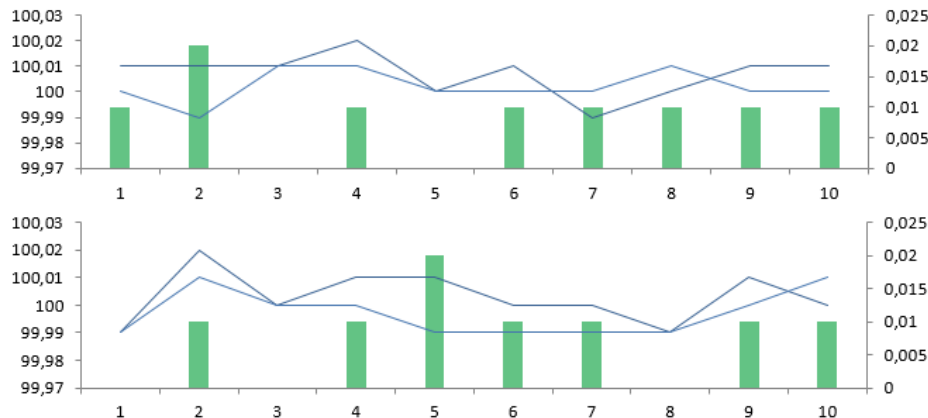
Cgk: Indicator of the systematical deviation.

## Measurement capability Method 2

- Check 10 Parts, 2 times by 3 Operators each.
- Indices: %R&R (earlier %GR&R) (Repeatability & Reproducibility)
- Detected Influences: Measurement System; Operator



# Measurement capability Method 2



## Characteristics

	Varianz	Sigma		10%
Repeatability	0,000068	0,008216	%EV = 8,46	
Reproducibility	0,000013	0,003613	%AV = 3,72	
Interaction	0,000000	0	%IA =	
Gauge distribution	0,000081	0,008975275		

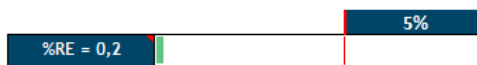
Repeatability

Reproducibility

Interaction

Number of distinct categories

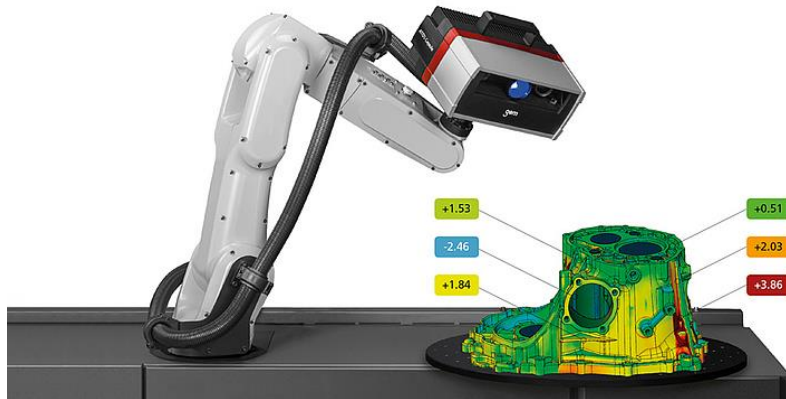
R&R or GR&R < 10%



Capability acc  
ANOVA  
NG

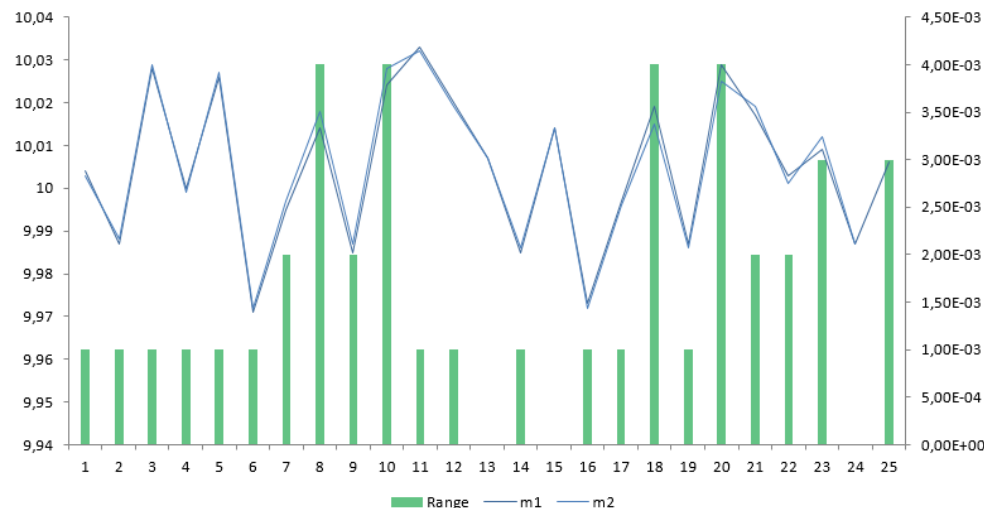
## Measurement capability Method 3

- Check 25 Parts, 2 times
- Indices: %R&R (Repeatability & Reproducibility)
- Detected Influences: Measurement System





# Measurement capability Method 3

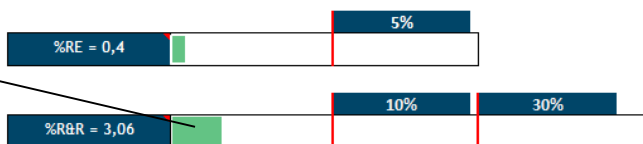


## Characteristics

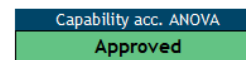
	Varianz	Sigma	
Repeatability	0,00000220	0,007639	%EV = 3,06
Repeatability & Reproducibility	0,00000220	0,007639	

Repeatability

R&R or GR&R < 10%



Number of distinct categories



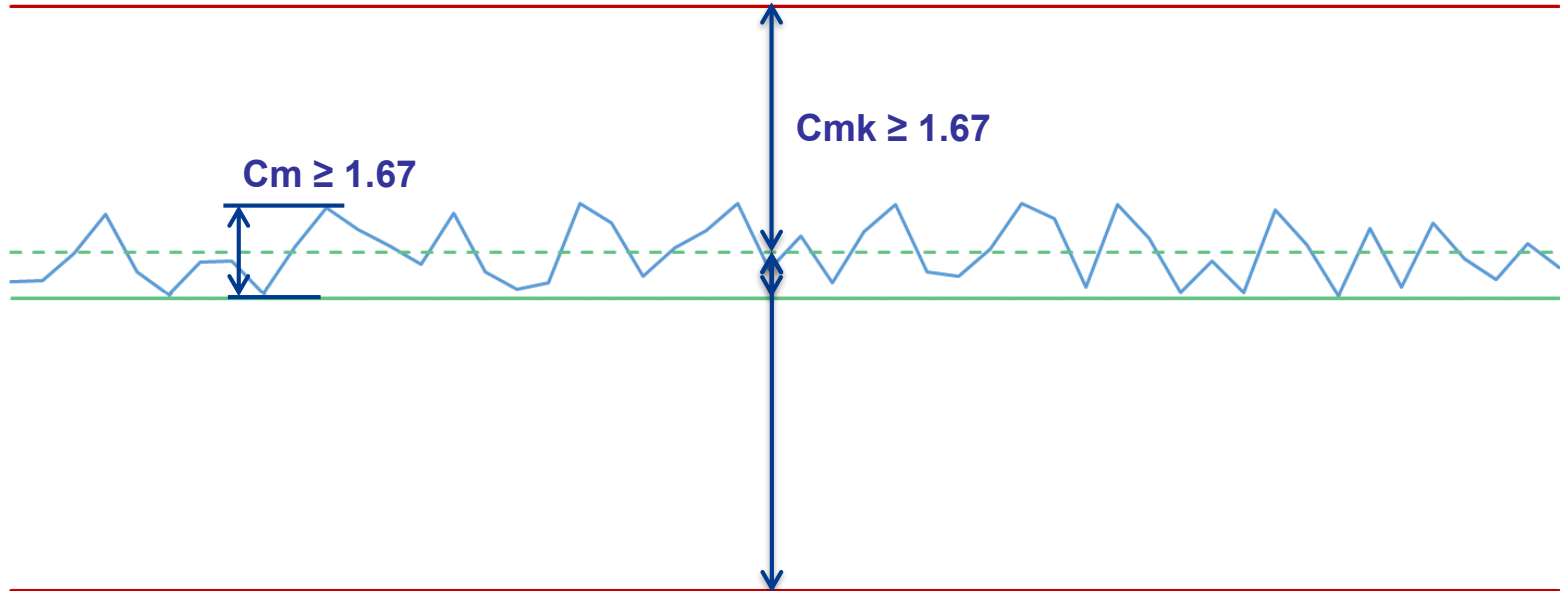
## Qualification Pyramid



## Machine capability

- Produce 50 Parts without adjust the machine
- Measure the parts according their production sequence
- Indices:  $C_m$ ;  $C_{mk}$  (Capability machine; Capability machine Katayori)
- Detected Influences: Machine

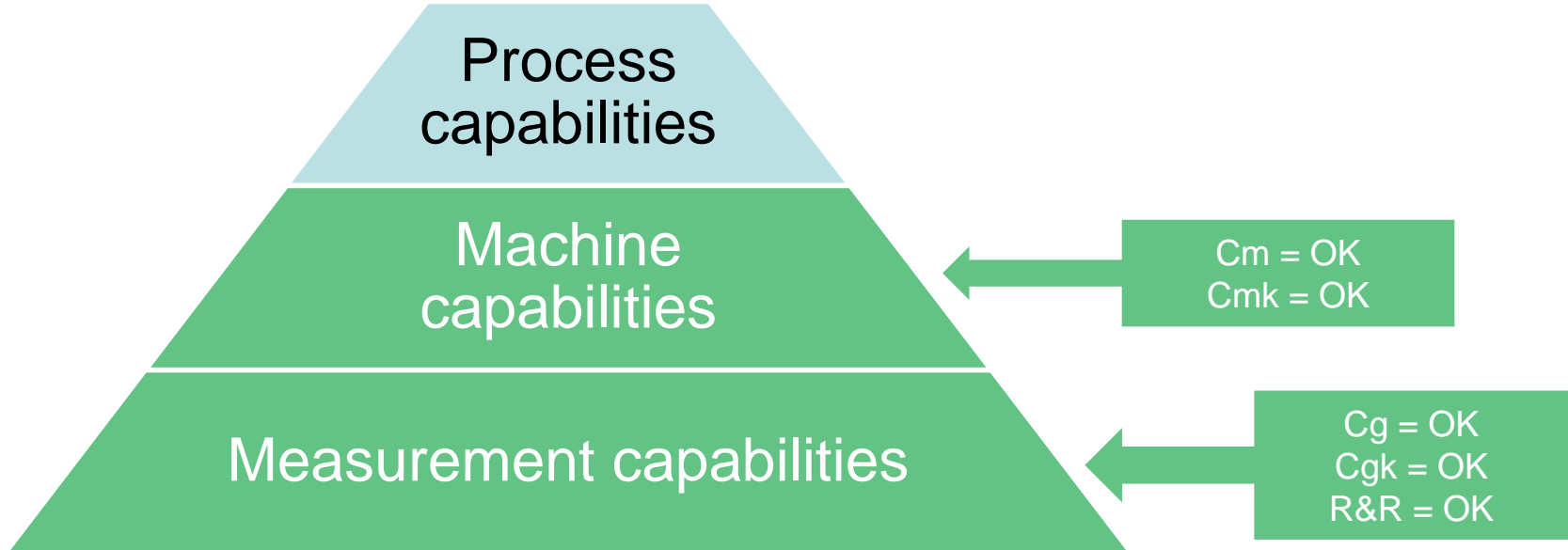
# Machine capability



Cm: Indicator for the spread width.

Cmk: Indicator of the distance to the next specification limit.

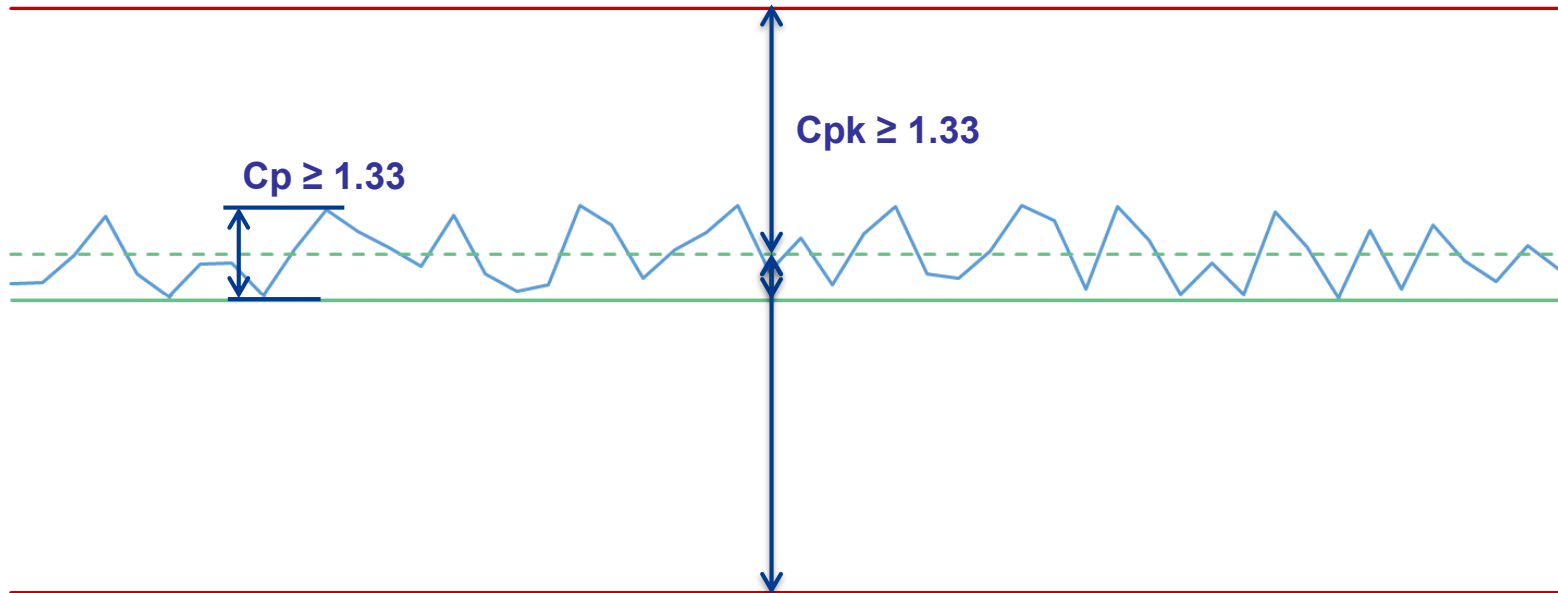
# Qualification Pyramid



## Process capability

- Produce 125 Parts over 4 shifts with all influences
- Measure the parts according their production sequence
- Indices:  $C_p$ ;  $C_{pk}$  (Capability process; Capability process Katayori)
- Detected Influences: All „M“ Influences

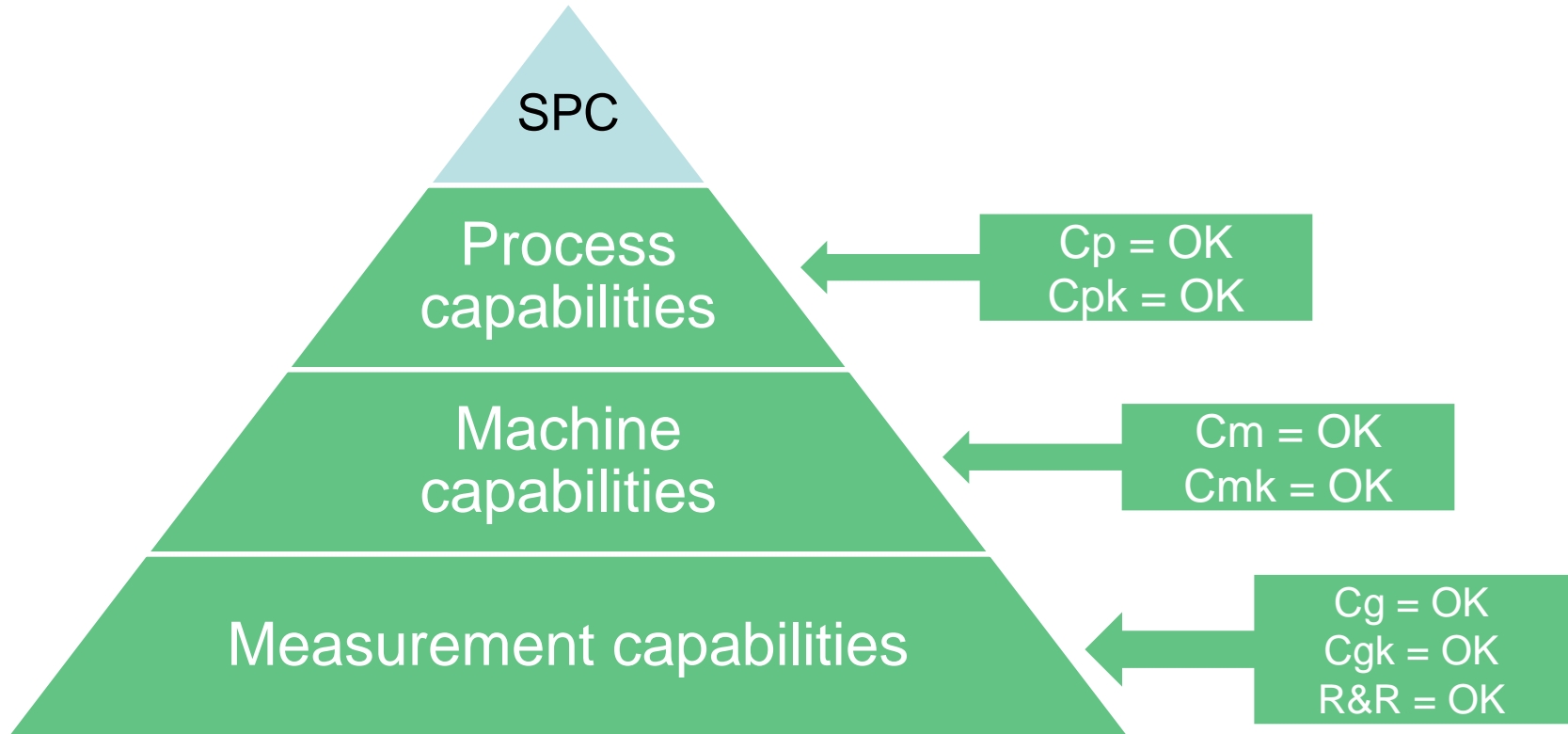
# Process capability



Cp: Indicator for the spread width.

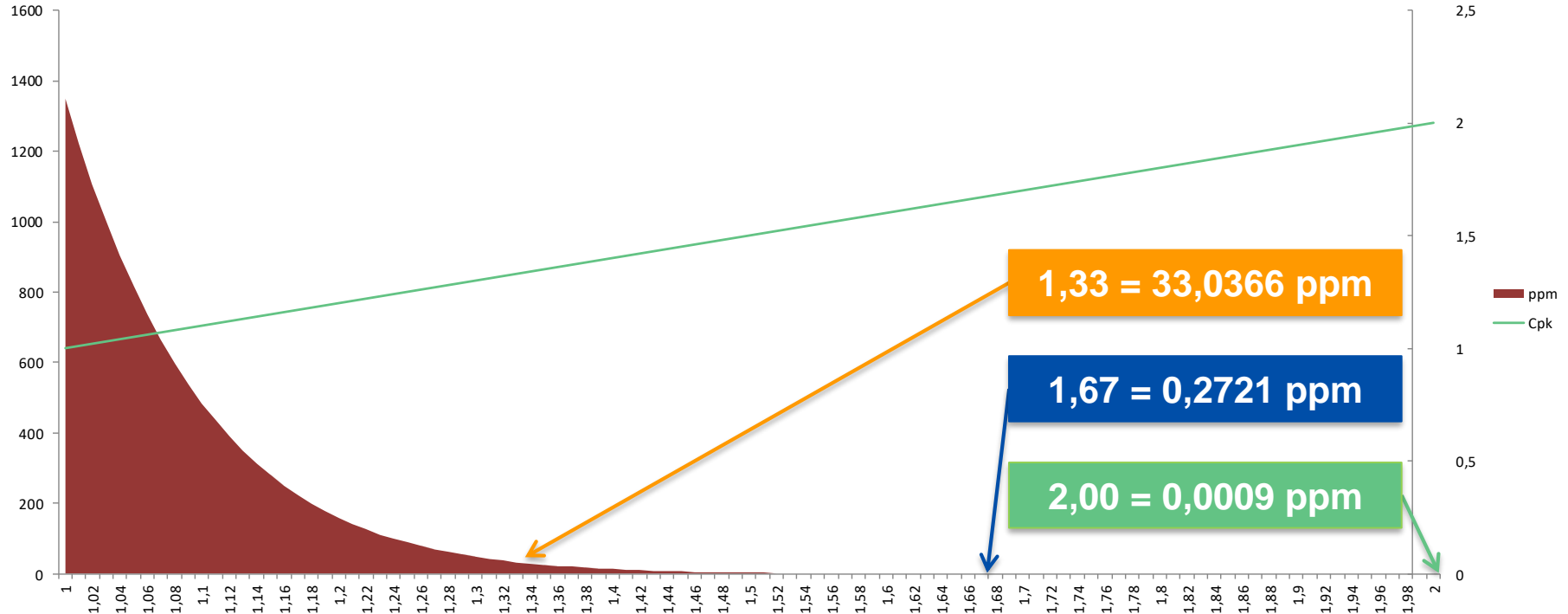
Cpk: Indicator of the distance to the next specification limit.

# Qualification Pyramid



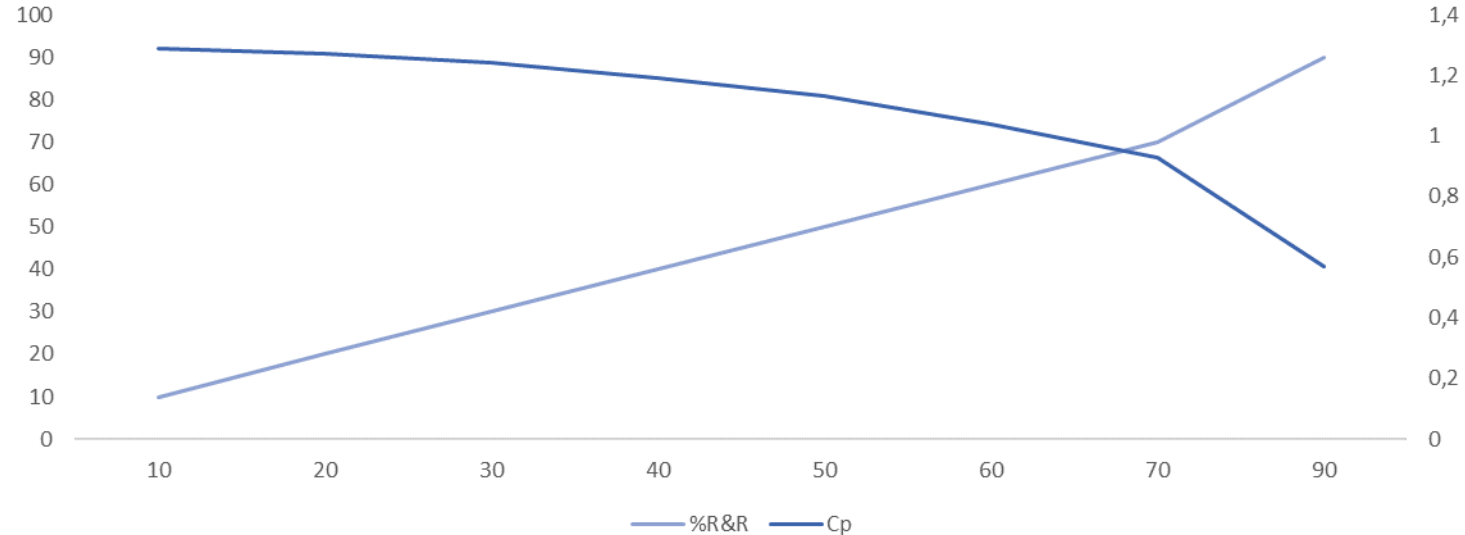


# Increasing requirements



If a normal distribution is proven, there is a direct connection between Cpk and ppm. Due to cost reduction and quality improvement, Cpk values increasing in the last 20 years.

# Connection between GRR% and Cp



Actual	GRR%							
	10	20	30	40	50	60	70	90
	Cp calculated by Tolerance							
1.3	1.29	1.27	1.24	1.19	1.13	1.04	0.93	0.57

Further there is a direct connection between Cp and the %R&R values (previously %GR&R). The larger the %R&R value, the smaller the Cp value and therefore also the Cpk.